

Application/Control No.	Applicant(s)/Patent under Reexamination
10/072,185	LIU ET AL.
Examiner	Art Unit
Michael Szperka	1644

	SEARCHED			
Class	Subclass	Date	Examiner	
424	185.1 192.1 93.71	7/19/2005	MS	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated inventor search Liu, Shih-Jen Lo, Wei-Yu	7/19/2005	MS
Updated EAST search (USPAT US-PGPUB EPO JPO DERWENT) see search notes	7/19/2005	MS
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